

	TEST CONDITIONS					TEST	LIMITS		No. TESTED	NOTE
	Vh	Va3 (Kv)	Va2	Va1 (Kv)	Vg		MIN.	MAX.		
a						<u>Capacitances</u> 1. Each X or Y plate to all other electrodes. 2. One X plate to one Y plate. 3. Grid to all other electrodes.	Measurements to be recorded and collated. Limits to be specified later.		100%	
b	4.0	0	0	0	0	Ih (A)	.95	1.15	100%	
c	4.0	6.0	Adjust for optimum focus	2.0	adjust as convenient	Va2 (V)	800	1100	100%	
d	4.0	6.0	ditto	2.0	Adjust to cut-off	Vg (V)	-40	-80	100%	
e	4.0	6.0	ditto	2.0	Adjust	SCREEN EFFICIENCY (c/w)	1.5	-	100%	1.
f	4.0	6.0	ditto	2.0	ditto	<u>DEFLECTION SENSITIVITY</u> 1. X plate (mm/v) 2. Y plate (mm/v)	$\frac{1800}{V_{a3}}$ $\frac{1000}{V_{a3}}$	$\frac{2100}{V_{a3}}$ $\frac{1300}{V_{a3}}$	100%	
g	4.0	6.0	ditto	2.0	ditto	<u>Deviation of spot from centre of screen (mm)</u>	-	10	100%	
h	4.0	6.0	ditto	2.0	ditto	<u>SPOT SIZE (mm)</u>	-	1	100%	
j	0	0	0	0	0	<u>ELECTRODE INSULATION RESISTANCE</u> 1. g/c (M Ω) 2. g/H (M Ω)	10 1		100%	
k	Set Vg to Cut off as per test d. Then readjust as Note 1.					Reduction in V mod as compared with test d	25	45.	100%	1.

NOTES 1. Vg adjusted to give 5 e.f.c. on a 20 cm/16 cm raster.

